

L Number	Hits	Search Text	DB	Time stamp
4	10	(4754215, 4862460, 5214654, 5314492, "5739778").pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/21 18:01
-	11768	test\$3 near memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 14:02
-	55309	test\$3 with memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 14:02
-	36	(test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 14:18
-	8	(test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 16:59
-	0	((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 17:10
-	1	((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 17:10
-	2	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 17:10
-	36	(BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 17:10
-	52	((test\$3 near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/03/29 17:12